



SBAS035B – FEBRUARY 1995 – REVISED FEBRUARY 2005

# 12-Bit, 40MHz Sampling ANALOG-TO-DIGITAL CONVERTER

# **FEATURES**

LOW POWER: 390mWINTERNAL REFERENCE

WIDEBAND TRACK-AND-HOLD: 65MHz

● SINGLE +5V SUPPLY

# **APPLICATIONS**

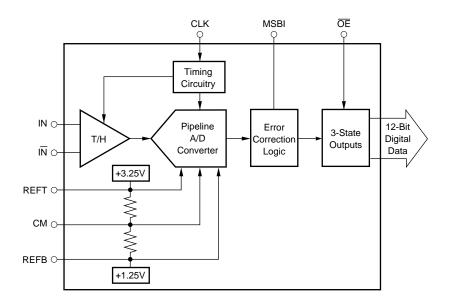
- IF AND BASEBAND DIGITIZATION
- DIGITAL COMMUNICATIONS
- ULTRASOUND IMAGING
- GAMMA CAMERAS
- TEST INSTRUMENTATION
- CCD IMAGING Copiers Scanners Cameras
- VIDEO DIGITIZING

# DESCRIPTION

The ADS800 is a low-power, monolithic 12-bit, 40MHz Analog-to-Digital (A/D) converter utilizing a small geometry CMOS process. This complete converter includes a 12-bit quantizer, wideband track-and-hold, reference, and three-state outputs. It operates from a single +5V power supply and can be configured to accept either differential or single-ended input signals.

The ADS800 employs digital error correction to provide excellent Nyquist differential linearity performance for demanding imaging applications. Its low distortion, high SNR, and high oversampling capability give it the extra margin needed for telecommunications, test instrumentation, and video applications.

This high-performance A/D converter is specified over temperature for AC and DC performance at a 40MHz sampling rate. The ADS800 is available in an SO-28 package.





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#### ABSOLUTE MAXIMUM RATINGS(1)

+V <sub>s</sub>	+6V
Analog Input	
Logic Input	0V to (+V <sub>s</sub> + 300mV)
Case Temperature	+100°C
Junction Temperature	+150°C
Storage Temperature	+125°C
External Top Reference Voltage (REFT)	+3.4V Max
External Bottom Reference Voltage (REFB)	+1.1V Min

NOTE: (1) Stresses above these ratings may permanently damage the device.



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### PACKAGE/ORDERING INFORMATION(1)

PRODUCT	PACKAGE-LEAD	PACKAGE DESIGNATOR	SPECIFIED TEMPERATURE RANGE	PACKAGE MARKING	ORDERING NUMBER	TRANSPORT MEDIA, QUANTITY
ADS800U	SO-28	DW	-40°C to +85°C	ADS800U	ADS800U	Rails, 28

NOTE: (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

# **ELECTRICAL CHARACTERISTICS**

At T<sub>A</sub> = +25°C, V<sub>S</sub> = +5V, Sampling Rate = 40MHz, and with a 50% duty cycle clock having a 2ns rise-and-fall time, unless otherwise noted.

PARAMETER   CONDITIONS   TEMP   MiN   TYP   MAX   UNITS					ADS800U			
Specified Temperature Range Operating Temperature Range	PARAMETER	CONDITIONS	TEMP	MIN	TYP MAX		UNITS	
Operating Temperature Range   TAMBIENT   -40   +85   °C    -40   ANALOG INPUT   Substitution   -40   +85   °C    -40   ANALOG INPUT   Substitution   -40   +85   °C    -40   ANALOG INPUT   Substitution   -40   -40   +85   °C    -40   ANALOG INPUT   Substitution   -40   -40   -40    -40   ANALOG INPUT   Substitution   -40   -40   -40    -40   ANALOG INPUT   Substitution   -40   -40   -40    -40   ANALOG INPUT   -425°C   -40   -40   -40    -40   AU					12			
ANALOG INPUT   Differential Full-Scale Input Range   Both Inputs, 180° Out-of-Phase   Full-Scale Input Range   Common-Mode Voltage   Analog Input Bandwidth (~3dB)   Small-Signal   Full-Power   OdBFS Input   OdBFS   OdBFS   OdBFS Input   OdBFS I				-				
Differential Full-Scale Input Range   Both Inputs, 180° Out-of-Phase   Full Phase   Page	Operating Temperature Range	T <sub>AMBIENT</sub>		-40		+85	°C	
180° Out-of-Phase	ANALOG INPUT							
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Differential Full-Scale Input Range	' '		+1.25		+3.25	V	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Common-Mode Voltage	100 041 011 11400			+2.25		V	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$								
Full-Power Input Impedance         0 dBFS Input $+25^{\circ}\text{C}$ 65 1.25    4         MHz MΩ    pF           DIGITAL INPUT Logic Family Convert Command         Start Conversion         TTL/HCT Compatible CMOS Falling Edge         TTL/HCT Compatible CMOS Falling Edge           ACCURACY(2) Gain Error $f_S = 2.5\text{MHz}$ $+25^{\circ}\text{C}$ $\pm 0.4$ $\pm 1.5$ $\pm 0.4$ $\pm 1.5$ $\pm 0.6$ $\pm 2.5$ $\pm 0.4$ $\pm 1.5$ $\pm 0.6$	• • • • • • • • • • • • • • • • • • • •	-20dBFS <sup>(1)</sup> Input	+25°C		400		MHz	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Full-Power	0dBFS Input	+25°C		65		MHz	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Input Impedance	, , ,			1.25    4		MΩ    pF	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	DIGITAL INPUT							
ACCURACY(2)         fs = 2.5MHz + 25°C         ±0.4         ±1.5         %           Gain Drift         ±0.6         ±2.5         %           Power-Supply Rejection of Gain Input Offset Error $\Delta + V_S = \pm 5\%$ +25°C         0.01         0.15         %FSR/% Power-Supply Rejection of Offset $\Delta + V_S = \pm 5\%$ +25°C         0.01         0.15         %FSR/% Power-Supply Rejection of Offset $\Delta + V_S = \pm 5\%$ +25°C         0.02         0.15         %FSR/% Power-Supply Rejection of Offset $\Delta + V_S = \pm 5\%$ +25°C         0.02         0.15         %FSR/% Power-Supply Rejection of Offset $\Delta + V_S = \pm 5\%$ +25°C         0.02         0.15         %FSR/% Power-Supply Rejection of Offset $\Delta + V_S = \pm 5\%$ +25°C         0.02         0.15         %FSR/% Power-Supply Rejection of Offset $\Delta + V_S = \pm 5\%$ +25°C         0.02         0.15         %FSR/% Power-Supply Rejection of Offset $\Delta + V_S = \pm 5\%$ $\Delta + V_S = \pm 5$	Logic Family			TTL/H	CT Compatible	CMOS		
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	Convert Command	Start Conversion			Falling Edge	l		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	ACCURACY <sup>(2)</sup>		f <sub>S</sub> = 2.5MHz					
Gain Drift $\Delta + V_S = \pm 5\%$ $\pm 25^{\circ}C$ $\pm 95$ $\pm 95$ $\pm 95$ $\pm 95^{\circ}C$ $\pm 2.6$ $\pm 2.6$ $\pm 3.5$ $\pm 2.6$ $\pm 3.5$ $\pm 3.$	Gain Error		+25°C		±0.4	±1.5	%	
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$			Full		±0.6	±2.5	%	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Gain Drift				±95		ppm/°C	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Power-Supply Rejection of Gain	$\Delta + V_S = \pm 5\%$	+25°C		0.01	0.15	%FSR/%	
CONVERSION CHARACTERISTICS         10k         40M         Sample/s Convert Cycle           DYNAMIC CHARACTERISTICS         Differential Linearity Error $f = 500 \text{kHz}$ $t_H = 13 \text{ns}^{(3)}$ $+25^{\circ}\text{C}$ $\pm 0.6$ $\pm 1.0$ LSB $f = 12 \text{MHz}$ $t_H = 13 \text{ns}^{(3)}$ $+25^{\circ}\text{C}$ $\pm 0.6$ $\pm 1.0$ LSB           No Missing Codes $t_H = 13 \text{ns}^{(3)}$ $+25^{\circ}\text{C}$ $\pm 0.4$ $\pm 1.0$ LSB           No Missing Codes $t_H = 13 \text{ns}^{(3)}$ $+25^{\circ}\text{C}$ $\pm 0.4$ $\pm 1.0$ LSB           Integral Linearity Error at $f = 500 \text{kHz}$ $t_H = 13 \text{ns}^{(3)}$ $+25^{\circ}\text{C}$ $\pm 0.4$ $\pm 1.0$ LSB           Spurious-Free Dynamic Range (SFDR) $t_H = 13 \text{ns}^{(3)}$	Input Offset Error		Full		±2.6	±3.5	%	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Power-Supply Rejection of Offset	$\Delta$ +V <sub>S</sub> = ±5%	+25°C		0.02	0.15	%FSR/%	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	CONVERSION CHARACTERISTICS							
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Sample Rate			10k		40M	Sample/s	
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	Data Latency				6.5		Convert Cycle	
$\begin{array}{cccccccccccccccccccccccccccccccccccc$								
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	•	$t_{\rm tr} = 13 \text{ns}^{(3)}$	+25°C		+0.6	+1.0	LSB	
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	. 0002	ι, ιοιιο						
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	f = 12MHz					+1.0		
No Missing Codes $t_H = 13 ns^{(3)}$ $t_H = 1$	1 – 1211112				_		_	
Integral Linearity Error at f = 500kHz   Full   ±1.9   LSB	No Missing Codes	$t_{\perp} = 13 \text{ns}^{(3)}$						
Spurious-Free Dynamic Range (SFDR)         +25°C         65         72         dBFS           f = 500kHz (-1dBFS input)         Full         60         66         dBFS           f = 12MHz (-1dBFS input)         +25°C         58         61         dBFS		,					-	
f = 500kHz (-1dBFS input)								
Full 60 66 dBFS +25°C 58 61 dBFS			+25°C	65	72		dBFS	
f = 12MHz (-1dBFS input) +25°C 58 61 dBFS					· -			
	f = 12MHz (-1dBFS input)		· ·					
	(		Full	55	61		dBFS	

NOTES: (1) dBFS refers to dB below Full-Scale. (2) Percentage accuracies are referred to the internal A/D converter Full-Scale Range of 4Vp-p. (3) To assure DNL and no missing code performance, see timing diagram footnote 2. (4) IMD is referred to the larger of the two input signals. If referred to the peak envelope signal (=0dB), the intermodulation products will be 7dB lower. (5) No "rollover" of bits.



# **ELECTRICAL CHARACTERISTICS (Cont.)**

At  $T_A = +25^{\circ}C$ ,  $V_S = +5V$ , Sampling Rate = 40MHz, and with a 50% duty cycle clock having a 2ns rise-and-fall time, unless otherwise noted.

				ADS800U		
PARAMETER	ARAMETER CONDITIONS		MIN	TYP	MAX	UNITS
DYNAMIC CHARACTERISTICS (Cont.)						
2-Tone Intermodulation Distortion (IMD)(4	)					
f = 4.4MHz and 4.5MHz (-7dBFS each	tone)	+25°C		-63		dBc
		Full		-62		dBc
Signal-to-Noise Ratio (SNR)						
f = 500kHz (-1dBFS input)		+25°C	61	64		dB
		Full	57	63		dB
f = 12MHz (-1dBFS input)		+25°C	61	62		dB
		Full	56	62		dB
Signal-to-(Noise + Distortion) (SINAD)						
f = 500kHz (-1dBFS input)		+25°C	59	63		dB
		Full	54	64		dB
f = 12MHz (-1dBFS input)		+25°C	56	58		dB
		Full	51	57		dB
Differential Gain Error	NTSC or PAL	+25°C		0.5		%
Differential Phase Error	NTSC or PAL	+25°C		0.1		degrees
Aperture Delay Time		+25°C		2		ns
Aperture Jitter		+25°C		7		ps rms
Over-Voltage Recovery Time <sup>(5)</sup>	1.5x Full-Scale Input	+25°C		2		ns
OUTPUTS						
Logic Family			TTL/H	CT Compatible	CMOS	
Logic Coding		Logic Selectable		SOB or BTC	 	
Logic Levels	Logic "LO",	Full	0		0.4	V
g	$C_1 = 15pF max$					-
	Logic "HI",	Full	+2.5		+V <sub>S</sub>	V
	$C_1 = 15pF max$				3	
3-State Enable Time				20	40	ns
3-State Disable Time		Full		2	10	ns
POWER-SUPPLY REQUIREMENTS						
Supply Voltage: +V <sub>S</sub>	Operating	Full	+4.75	+5.0	+5.25	V
Supply Current: +I <sub>S</sub>	Operating	+25°C		78	93	mA
	Operating	Full		78	97	mA
Power Consumption	Operating	+25°C		390	465	mW
	Operating	Full		390	485	mW
Thermal Resistance, $\theta_{IA}$						
SO-28				75		°C/W

NOTES: (1) dBFS refers to dB below Full-Scale. (2) Percentage accuracies are referred to the internal A/D converter Full-Scale Range of 4Vp-p. (3) To assure DNL and no missing code performance, see timing diagram footnote 2. (4) IMD is referred to the larger of the two input signals. If referred to the peak envelope signal (=0dB), the intermodulation products will be 7dB lower. (5) No "rollover" of bits.

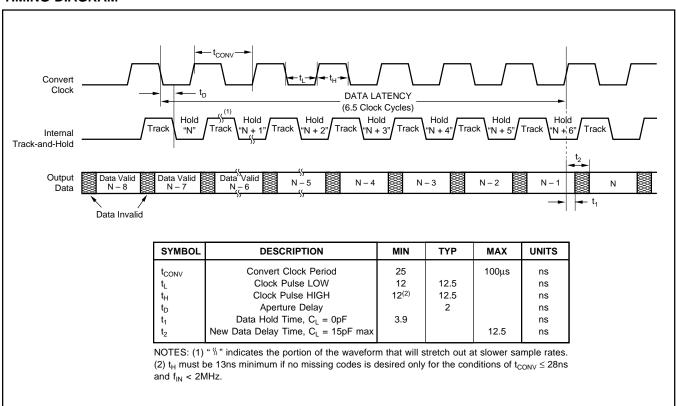
### **PIN CONFIGURATION**

#### **Top View** so 0 GND 28 GND В1 2 27 ĪN B2 3 26 IN 4 GND B3 25 24 B4 5 $+V_S$ B5 6 23 REFT 7 22 CM B6 ADS800 8 21 REFB B7 В8 9 20 $+V_S$ 19 MSBI В9 10 18 ŌĒ B10 11 B11 12 17 $+V_S$ B12 13 16 CLK 15 GND 14

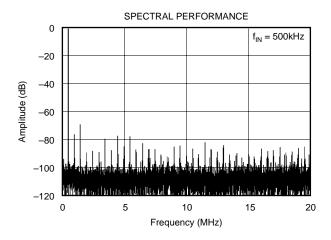
### **PIN DESCRIPTIONS**

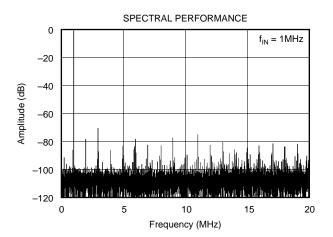
PIN	DESIGNATOR	DESCRIPTION
1	GND	Ground
2	B1	Bit 1, Most Significant Bit
3	B2	Bit 2
4	B3	Bit 3
5	B4	Bit 4
6	B5	Bit 5
7	B6	Bit 6
8	B7	Bit 7
9	B8	Bit 8
10	B9	Bit 9
11	B10	Bit 10
12	B11	Bit 11
13	B12	Bit 12, Least Significant Bit
14	GND	Ground
15	+V <sub>S</sub>	+5V Power Supply
16	CLK	Convert Clock Input, 50% Duty Cycle
17	+V <sub>S</sub>	+5V Power Supply
18	ŌĒ	HI: High Impedance State. LO or Floating: Nor-
		mal Operation. Internal pull-down resistors.
19	MSBI	Most Significant Bit Inversion, HI: MSB inverted
		for complementary output. LO or Floating: Straight
		output. Internal pull-down resistors.
20	+V <sub>S</sub>	+5V Power Supply
21	REFB	Bottom Reference Bypass. For external bypass-
		ing of internal +1.25V reference.
22	СМ	Common-Mode Voltage. It is derived by (REFT +
		REFB)/2.
23	REFT	Top Reference Bypass. For external bypassing
		of internal +3.25V reference.
24	+V <sub>S</sub>	+5V Power Supply
25	GND	Ground
26	IN	Input
27	IN ON D	Complementary Input
28	GND	Ground

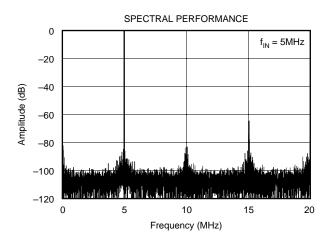
### **TIMING DIAGRAM**

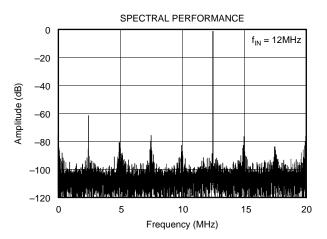


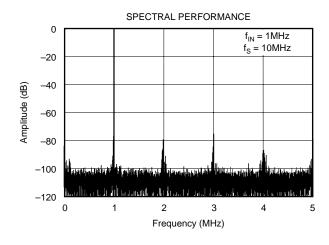
# TYPICAL CHARACTERISTICS

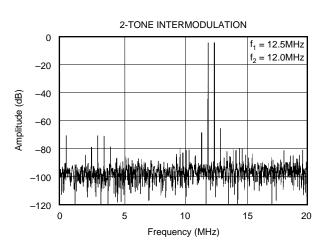






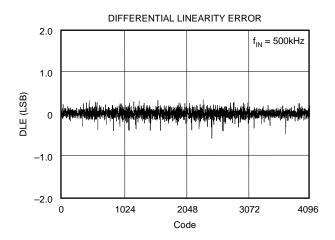


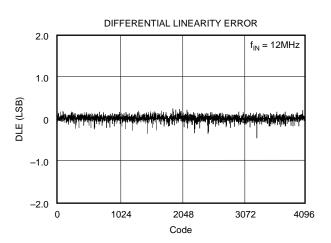


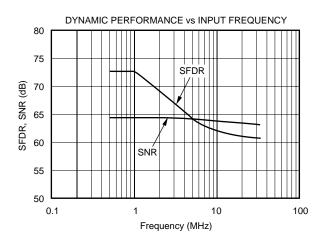


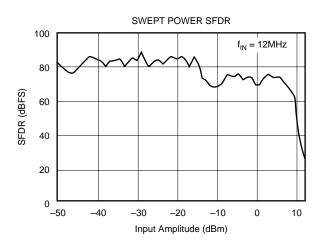


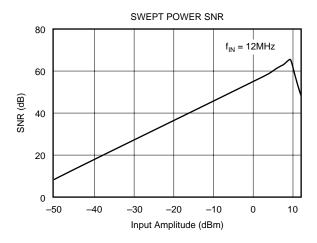
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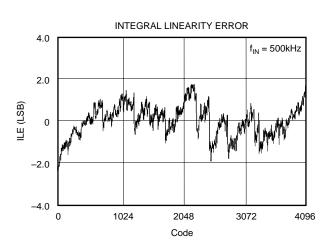






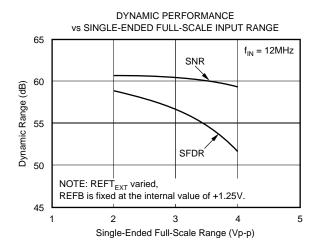


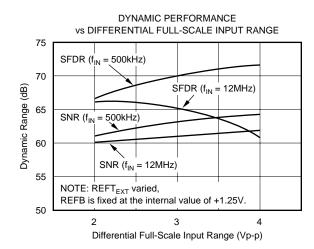


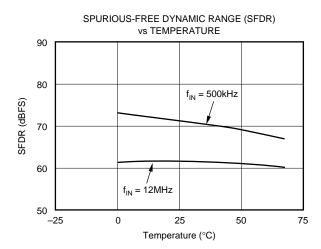


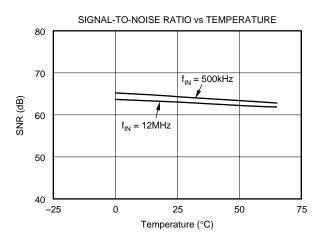


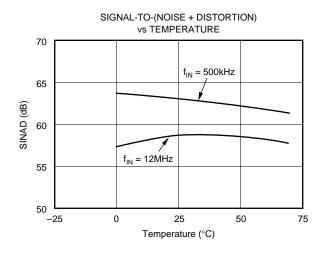
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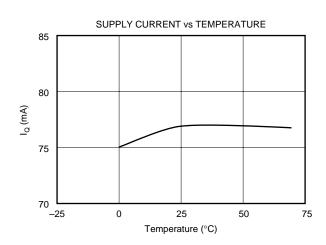




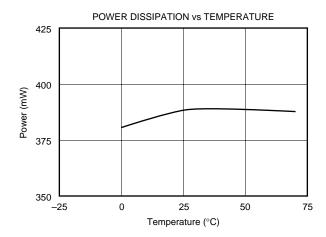


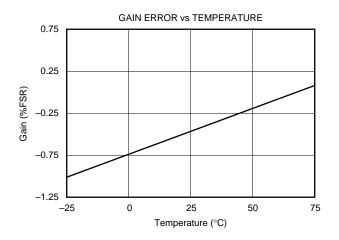


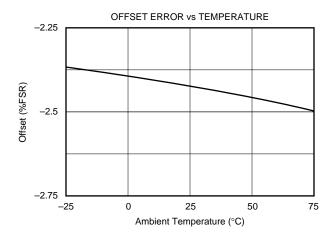


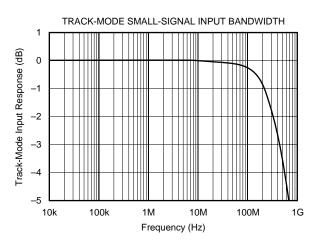


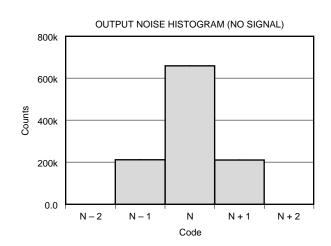
# **TYPICAL CHARACTERISTICS (Cont.)**













## THEORY OF OPERATION

The ADS800 is a high-speed, sampling A/D converter with pipelining. It uses a fully differential architecture and digital error correction to ensure 12-bit resolution. The differential track-and-hold circuit is shown in Figure 1. The switches are controlled by an internal clock which has a non-overlapping 2-phase signal,  $\phi 1$  and  $\phi 2$ . At the sampling time, the input signal is sampled on the bottom plates of the input capacitors. In the next clock phase,  $\phi 2$ , the bottom plates of the input capacitors are connected together and the feedback capacitors are switched to the op amp output. At this time, the charge redistributes between  $C_1$  and  $C_H$ , completing one track-and-hold cycle. The differential output is a held DC representation of the analog input at the sample time. The track-and-hold circuit can also convert a single-ended input signal into a fully differential signal for the quantizer.

The pipelined quantizer architecture has 11 stages with each stage containing a 2-bit quantizer and a 2-bit Digital-to-Analog Converter (DAC), as shown in Figure 2. Each 2-bit quantizer stage converts on the edge of the sub-clock, which is twice the frequency of the externally applied clock. The output of each quantizer is fed into its own delay line to time-

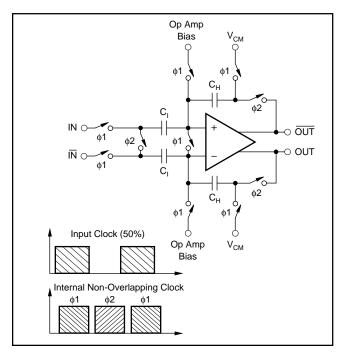


FIGURE 1. Input Track-and-Hold Configuration with Timing Signals.

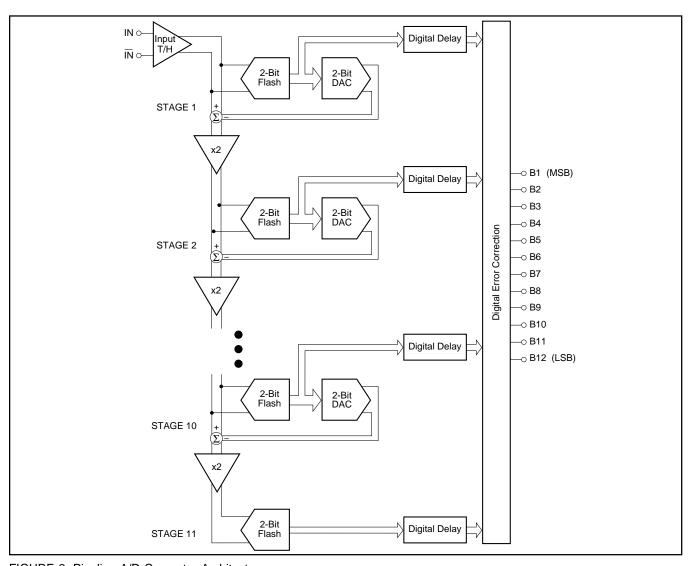


FIGURE 2. Pipeline A/D Converter Architecture.



align it with the data created from the following quantizer stages. This aligned data is fed into a digital error correction circuit which can adjust the output data based on the information found on the redundant bits. This technique gives the ADS800 excellent differential linearity and ensures no missing codes at the 12-bit level.

Since there are two pipeline stages per external clock cycle, there is a 6.5 clock cycle data latency from the start convert signal to the valid output data. The output data is available in Straight Offset Binary (SOB) or Binary Two's Complement (BTC) format.

### THE ANALOG INPUT AND INTERNAL REFERENCE

The analog input of the ADS800 can be configured in various ways and driven with different circuits, depending on the nature of the signal and the level of performance desired. The ADS800 has an internal reference that sets the full-scale input range of the A/D converter. The differential input range has each input centered around the common-mode of +2.25V, with each of the two inputs having a full-scale range of +1.25V to +3.25V. Since each input is 2Vp-p and 180° outof-phase with the other, a 4V differential input signal to the quantizer results. As shown in Figure 3, the positive full-scale reference (REFT) and the negative full-scale (REFB) are brought out for external bypassing. In addition, the commonmode voltage (CM) may be used as a reference to provide the appropriate offset for the driving circuitry. However, care must be taken not to appreciably load this reference node. For more information regarding external references, singleended input, and ADS800 drive circuits, refer to the applications section.

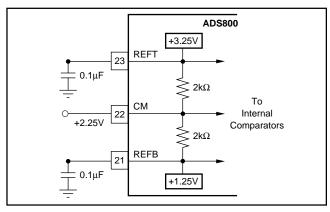


FIGURE 3. Internal Reference Structure.

### **CLOCK REQUIREMENTS**

The CLK pin accepts a CMOS level clock input. Both the rising and falling edges of the externally applied clock control the various interstage conversions in the pipeline. Therefore, the clock signal's jitter, rise-and-fall times, and duty cycle can affect conversion performance.

- Low clock jitter is critical to SNR performance in frequency-domain signal environments.
- Clock rise-and-fall times should be as short as possible (< 2ns for best performance).</li>

• For most applications, the clock duty should be set to 50%. However, for applications requiring no missing codes, a slight skew in the duty cycle will improve DNL performance for conversion rates > 35MHz and input frequencies < 2MHz (see Timing Diagram) in the SO package. For the best performance in the SSOP package, the clock should be skewed under all input frequencies with conversion rates > 35MHz. A possible method for skewing the 50% duty cycle source is shown in Figure 4.

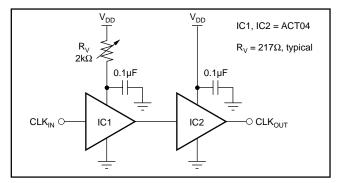


FIGURE 4. Clock Skew Circuit.

#### **DIGITAL OUTPUT DATA**

The 12-bit output data is provided at CMOS logic levels. The standard output coding is Straight Offset Binary (SOB) where a full-scale input signal corresponds to all "1's" at the output, as shown in Table 1. This condition is met with pin 19 "LO" or Floating due to an internal pull-down resistor. By applying a logic "HI" voltage to this pin, a Binary Two's Complement (BTC) output will be provided where the most significant bit is inverted. The digital outputs of the ADS800 can be set to a high-impedance state by driving  $\overline{\text{OE}}$  (pin 18) with a logic "HI". Normal operation is achieved with pin 18 "LO" or Floating due to internal pull-down resistors. This function is provided for testability purposes and is not meant to drive digital buses directly or be dynamically changed during the conversion process.

	OUTPUT CODE					
DIFFERENTIAL INPUT <sup>(1)</sup>	SOB PIN 19 FLOATING or LO	BTC PIN 19 HI				
+FS (IN = +3.25V, IN = +1.25V) +FS - 1LSB +FS - 2LSB +3/4 Full-Scale +1/2 Full-Scale +1/4 Full-Scale +1LSB Bipolar Zero (IN = IN = +2.25V) -1LSB -1/4 Full-Scale -1/2 Full-Scale -3/4 Full-Scale -FS + 1LSB	11111111111 11111111111 11111111110 111000000	01111111111 01111111111 01111111111 011000000				
-FS (IN = +1.25V, $\overline{IN}$ = +3.25V) NOTE: (1) In the single-ended input	000000000000	10000000000				

TABLE I. Coding Table for the ADS800.



## **APPLICATIONS**

#### **DRIVING THE ADS800**

The ADS800 has a differential input with a common-mode of +2.25V. For AC-coupled applications, the simplest way to create this differential input is to drive the primary winding of a transformer with a single-ended input. A differential output is created on the secondary if the center tap is tied to the common-mode voltage of +2.25V, as per Figure 5. This transformer-coupled input arrangement provides good highfrequency AC performance. It is important to select a transformer that gives low distortion and does not exhibit core saturation at full-scale voltage levels. Since the transformer does not appreciably load the ladder, there is no need to buffer the Common-Mode (CM) output in this instance. In general, it is advisable to keep the current draw from the CM output pin below 0.5µA to avoid nonlinearity in the internal reference ladder. A FET input operational amplifier such as the OPA130 can provide a buffered reference for driving external circuitry. The analog IN and IN inputs should be bypassed with 22pF capacitors to minimize track-and-hold glitches and to improve high input frequency performance.

Figure 6 illustrates another possible low-cost interface circuit which utilizes resistors and capacitors in place of a transformer. Depending on the signal bandwidth, the component values should be carefully selected in order to maintain the

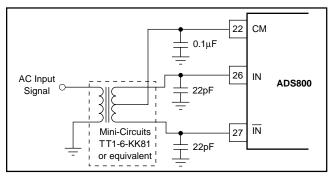


FIGURE 5. AC-Coupled Single-Ended to Differential Drive Circuit Using a Transformer.

product performance. The input capacitors,  $C_{IN}$ , and the input resistors,  $R_{IN}$ , create a high-pass filter with the lower corner frequency at  $f_C = 1/(2pR_{IN}C_{IN})$ . The corner frequency can be reduced by either increasing the value of  $R_{IN}$  or  $C_{IN}$ . If the circuit operates with a  $50\Omega$  or  $75\Omega$  impedance level, the resistors are fixed and only the value of the capacitor can be increased. Usually, AC-coupling capacitors are electrolytic or tantalum capacitors with values of  $1\mu F$  or higher. It should be noted that these large capacitors become inductive with increased input frequency, which could lead to signal amplitude errors or oscillation. To maintain a low AC-coupling impedance throughout the signal band, a small value (e.g.  $1\mu F$ ) ceramic capacitor could be added in parallel with the polarized capacitor.

Capacitors  $C_{SH1}$  and  $C_{SH2}$  are used to minimize current glitches resulting from the switching in the input track-and-hold stage and to improve signal-to-noise performance. These capacitors can also be used to establish a low-pass filter and effectively reduce the noise bandwidth. In order to create a real pole, resistors  $R_{SER1}$  and  $R_{SER2}$  were added in series with each input. The cutoff frequency of the filter is determined by  $f_C = 1/(2pR_{SER} \bullet (C_{SH} + C_{ADC}))$  where  $R_{SER}$  is the resistor in series with the input,  $C_{SH}$  is the external capacitor from the input to ground, and  $C_{ADC}$  is the internal input capacitance of the A/D converter (typically 4pF).

Resistors  $R_1$  and  $R_2$  are used to derive the necessary common-mode voltage from the buffered top and bottom references. The total load of the resistor string should be selected so that the current does not exceed 1mA. Although the circuit in Figure 6 uses two resistors of equal value so that the common-mode voltage is centered between the top and bottom reference (+2.25V), it is not necessary to do so. In all cases the center point,  $V_{CM}$ , should be bypassed to ground in order to provide a low-impedance AC ground.

If the signal needs to be DC coupled to the input of the ADS800, an operational amplifier input circuit is required. In the differential input mode, any single-ended signal must be modified to create a differential signal. This can be accomplished by

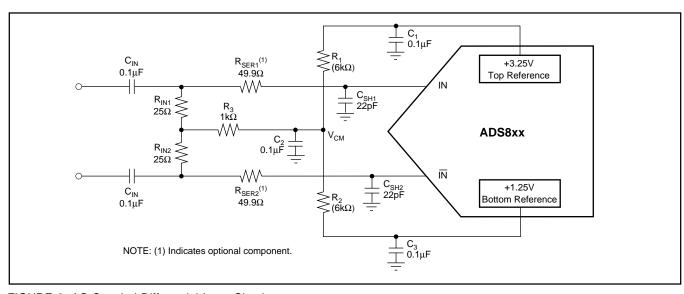


FIGURE 6. AC-Coupled Differential Input Circuit.



using two operational amplifiers, one in the noninverting mode for the input and the other amplifier in the inverting mode for the complementary input. The low distortion circuit in Figure 7 will provide the necessary input shifting required for signals centered around ground. It also employs a diode for output level shifting to ensure a low distortion +3.25V output swing. Other amplifiers can be used in place of the OPA842s if the lowest distortion is not necessary. If output level shifting circuits are not used, care must be taken to select operational amplifiers that give the necessary performance when swinging to +3.25V with a ±5V supply operational amplifier.

The ADS800 can also be configured with a single-ended input full-scale range of +0.25V to +4.25V by tying the complementary input to the common-mode reference volt-

age, as shown in Figure 8. This configuration will result in increased even-order harmonics, especially at higher input frequencies. However, this tradeoff may be quite acceptable for time-domain applications. The driving amplifier must give adequate performance with a +0.25V to +4.25V output swing in this case.

# EXTERNAL REFERENCES AND ADJUSTMENT OF FULL-SCALE RANGE

The internal reference buffers are limited to approximately 1mA of output current. As a result, these internal +1.25V and +3.25V references may be overridden by external references that have at least 18mA (at room temperature) of output drive capability. In this instance, the common-mode voltage will be

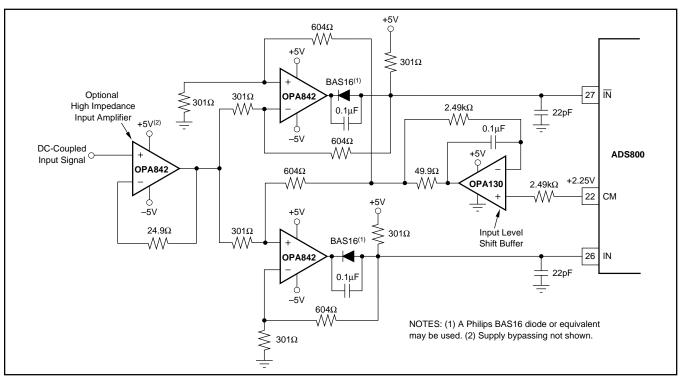


FIGURE 7. A Low Distortion DC-Coupled, Single-Ended to Differential Input Driver Circuit.

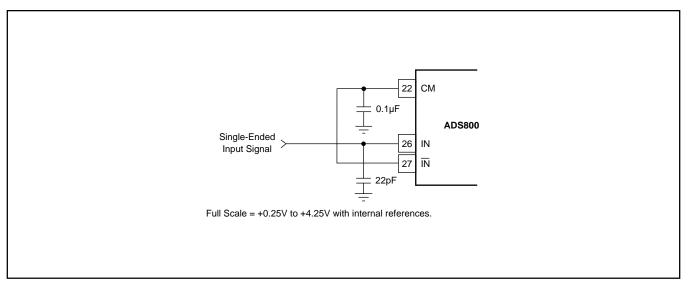


FIGURE 8. Single-Ended Input Connection.



set halfway between the two references. This feature can be used to adjust the gain error, improve gain drift, or to change the full-scale input range of the ADS800. Changing the full-scale range to a lower value has the benefit of easing the swing requirements of external input drive amplifiers. The external references can vary as long as the value of the external top reference (REFT<sub>EXT</sub>) is less than or equal to +3.4V, the value of the external bottom reference (REFB<sub>EXT</sub>) is greater than or equal to +1.1V, and the difference between the external references are greater than or equal to 1.5V.

For the differential configuration, the full-scale input range will be set to the external reference values that are selected. For the single-ended mode, the input range is 2 • (REFT<sub>EXT</sub> - REFB<sub>EXT</sub>), with the common-mode being centered at (REFT<sub>EXT</sub> + REFB<sub>EXT</sub>)/2. Refer to the typical characteristics for "Expected Performance vs Full-Scale Input Range".

The circuit in Figure 10 works completely on a single +5V supply. As a reference element, it uses the micro-power reference REF1004-2.5, which is set to a quiescent current of 0.1mA. Amplifier  $A_2$  is configured as a follower to buffer the +1.25V generated from the resistor divider. To provide the necessary current drive, a pull-down resistor,  $R_p$ , is added. Amplifier  $A_1$  is configured as an adjustable gain stage, with a range of approximately 1 to 1.32. The pull-up resistor again relieves the op amp from providing the full current drive. The value of the pull-up/down resistors is not critical and can be varied to optimize power consumption. The need for pull-up, pull-down resistors depends only on the drive capability of the selected drive amplifiers and thus can be omitted.

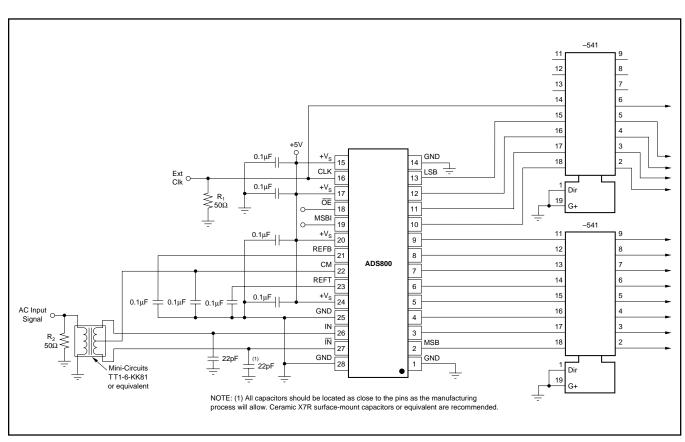


FIGURE 9. ADS800 Interface Schematic with AC-Coupling and External Buffers.



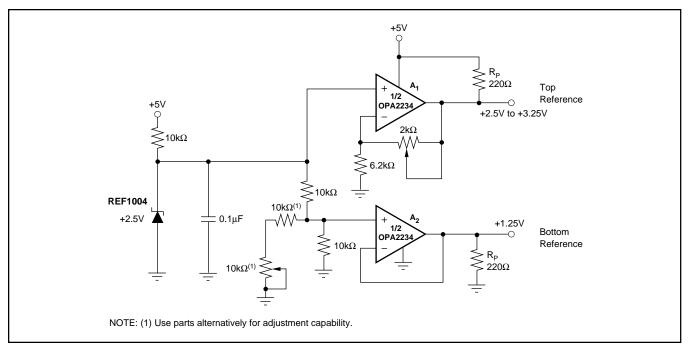


FIGURE 10. Optional External Reference to Set the Full-Scale Range Utilizing a Dual, Single-Supply Op Amp.

### PC BOARD LAYOUT AND BYPASSING

A well-designed, clean PC board layout will assure proper operation and clean spectral response. Proper grounding and bypassing, short lead lengths, and the use of ground planes are particularly important for high-frequency circuits. Multilayer PC boards are recommended for best performance but if carefully designed, a two-sided PC board with large, heavy ground planes can give excellent results. It is recommended that the analog and digital ground pins of the ADS800 be connected directly to the analog ground plane. In our experience, this gives the most consistent results. The A/D converter power-supply commons should be tied together at the analog ground plane. Power supplies should be bypassed with  $0.1\mu F$  ceramic capacitors as close to the pin as possible.

### **DYNAMIC PERFORMANCE TESTING**

The ADS800 is a high performance converter and careful attention to test techniques is necessary to achieve accurate results. Highly accurate phase-locked signal sources allow high resolution FFT measurements to be made without using data windowing functions. A low jitter signal generator such as the HP8644A for the test signal, phase-locked with a low jitter

HP8022A pulse generator for the A/D converter clock, gives excellent results. Low-pass filtering (or bandpass filtering) of test signals is absolutely necessary to test the low distortion of the ADS800. Using a signal amplitude slightly lower than full-scale will allow a small amount of "headroom" so that noise or DC offset voltage will not over-range the A/D converter and cause clipping on signal peaks.

### DYNAMIC PERFORMANCE DEFINITIONS

Signal-to-Noise-and-Distortion Ratio (SINAD):

2. Signal-to-Noise Ratio (SNR):

3. Intermodulation Distortion (IMD):

$$10 \log \frac{\text{Highest IMD Pr oduct Power (to 5th - order)}}{\text{Sinewave Signal Power}}$$

IMD is referenced to the larger of the test signals,  $f_1$  or  $f_2$ . Five "bins" either side of peak are used for calculation of fundamental and harmonic power. The "0" frequency bin (DC) is not included in these calculations as it is of little importance in dynamic signal processing applications.



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### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
ADS800U	OBSOLETE	SOIC	DW	28		TBD	Call TI	Call TI	-40 to 85	ADS800U	
ADS800U/1K	OBSOLETE	SOIC	DW	28		TBD	Call TI	Call TI	-40 to 85	ADS800U	

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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DW (R-PDSO-G28)

### PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AE.



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